


<b>Search Notes</b> 	<b>Application/Control No.</b> 10802010	<b>Applicant(s)/Patent Under Reexamination</b> CHUNG ET AL.
	<b>Examiner</b> Rutz, Jared I	<b>Art Unit</b> 2187

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in EAST and PALM	8/18/2006	jir
text and text limited classification search in EAST, see search history	8/18/2006	jir
Updated search in EAST	2/8/2007	jir

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner